

E-Beam VB6 UHR-EWF

- Substrate: 4" and 6" wafer; special piece parts (on request, minimum size 20 mm x 20 mm)
- High voltage: 100 kV
- Main field: $\leq 1310 \mu\text{m}$
- Resolution: $< 1 \text{ nm}$ (depends on main field size)

E-Beam lithography in extremely thick PMMA (3200 nm) with structural details in submicron range ($\sim 200 \text{ nm}$)

E-Beam lithography down to 20 nm scale in PMMA (resist thickness $< 100 \text{ nm}$).

Contact

See KNMF website or contact the KNMF User Office.

Features

- Aspect ratio up to 10 depending on geometry
- Structural details $\geq 20 \text{ nm}$
- Resist thickness up to 3200 nm
(e.g. for electroplating of high aspect ratio gold structures required for X-ray lithography)

Limitations/constraints

- Standard Resist: PMMA

Design rules

- Rounding of structural edges
- Design of dummy structures for stress reduction
- Homogeneous structure allocation (in case of subsequent electroplating)

Materials

Substrate materials: silicon, glass, metal

Other resist and substrate materials on request